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# Fault-Tolerant Digital Circuits: Protection Techniques, CAD Tools and Emerging Applications

Guest Editor:

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## Message from the Guest Editor

Reliability is a growing concern for electronic digital circuits. In this Special Issue, we are interested in exploring new protection techniques for electronic systems, CAD tools to perform reliability tests and novel applications, in different fields, which can benefit from the use of fault-tolerant circuits.

These topics include but not limited to:

- New protection techniques for digital circuits
- Fault-tolerant computer architectures
- Error correction codes (ECC) to increase reliability in innovative ways
- Signal and image processing systems with a focus on reliability
- CAD tools and methods to emulate error injection test processes
- Novel applications of fault tolerant digital circuits

Welcome to contribute.











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### **Editor-in-Chief**

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## **Message from the Editor-in-Chief**

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